MOSFET - Power, Single N-Channel, SO-8FL

30 V, 52 A

NTMFS4C09N

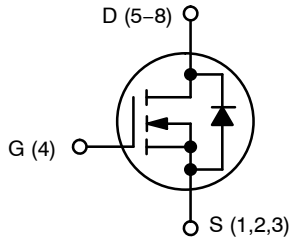
$V_{(BR)DSS}$	$R_{DS(ON)}$ MAX	I_D MAX
30 V	5.8 mΩ @ 10 V	52 A
	8.5 mΩ @ 4.5 V	

Features

- Low $R_{DS(on)}$ to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb−Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- CPU Power Delivery
- DC−DC Converters



N−CHANNEL MOSFET

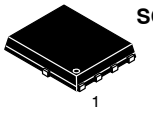
MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain−to−Source Voltage			V_{DSS}	30	V
Gate−to−Source Voltage			V_{GS}	±20	V
Continuous Drain Current $R_{\theta JA}$ (Note 2)	Steady State	T_A = 25°C	I_D	16.4	A
		T_A = 80°C		12.3	
Power Dissipation $R_{\theta JA}$ (Note 2)		T_A = 25°C	P_D	2.51	W
Continuous Drain Current $R_{\theta JA} \le 10$ s (Note 2)		T_A = 25°C	I_D	25.3	A
		T_A = 80°C		19.0	
Power Dissipation $R_{\theta JA} \le 10$ s (Note 2)		T_A = 25°C	P_D	6.0	W
Continuous Drain Current $R_{\theta JA}$ (Note 3)		T_A = 25°C	I_D	9.0	A
		T_A = 80°C		6.8	
Power Dissipation $R_{\theta JA}$ (Note 3)		T_A = 25°C	P_D	0.76	W
Continuous Drain Current $R_{\theta JC}$ (Note 2)		T_C = 25°C	I_D	52	A
		T_C =80°C		39	
Power Dissipation $R_{\theta JC}$ (Note 2)		T_C = 25°C	P_D	25.5	W
Pulsed Drain Current	T_A = 25°C, t_p = 10 μs		I_{DM}	146	A
Current Limited by Package		T_A = 25°C	I_{Dmax}	80	A
Operating Junction and Storage Temperature Range			T_J, T_{STG}	−55 to +150	°C
Source Current (Body Diode)			I_S	23	A
Drain to Source dV/dt			dV/d_t	7.0	V/ns
Single Pulse Drain−to−Source Avalanche Energy (T_J = 25°C, V_{GS} = 10 V, I_L = 29 A_{pk}, L = 0.1 mH, R_{GS} = 25 Ω) (Note 4)			E_{AS}	42	mJ
Lead Temperature for Soldering Purposes (1/8″ from case for 10 s)			T_L	260	°C

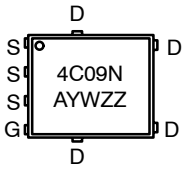
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

2. Surface−mounted on FR4 board using 1 sq−in pad, 1 oz Cu.
3. Surface−mounted on FR4 board using the minimum recommended pad size.
4. Parts are 100% tested at T_J = 25°C, V_{GS} = 10 V, I_L = 20 A_{pk}, EAS = 20 mJ.

MARKING DIAGRAMS



SO−8 FLAT LEAD CASE 488AA STYLE 1



A = Assembly Location
Y = Year
W = Work Week
ZZ = Lot Traceabililty

ORDERING INFORMATION

Device	Package	Shipping†
NTMFS4C09NT1G	SO−8 FL (Pb−Free)	1500 / Tape & Reel

DISCONTINUED (Note 1)

NTMFS4C09NT3G	SO−8 FL (Pb−Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

1. **DISCONTINUED:** This device is not recommended for new design. Please contact your **onsemi** representative for information. The most current information on this device may be available on www.onsemi.com.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction−to−Case (Drain)	$R_{\theta JC}$	4.9	°C/W
Junction−to−Ambient − Steady State (Note 5)	$R_{\theta JA}$	49.8	
Junction−to−Ambient − Steady State (Note 6)	$R_{\theta JA}$	164.6	
Junction−to−Ambient − (t ≤ 10 s) (Note 5)	$R_{\theta JA}$	21.0	

5. Surface−mounted on FR4 board using 1 sq−in pad, 1 oz Cu.
6. Surface−mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Typ	Max	Unit
OFF CHARACTERISTICS							
Drain−to−Source Breakdown Voltage	$V_{(BR)DSS}$	V_{GS} = 0 V, I_D = 250 μA		30			V
Drain−to−Source Breakdown Voltage (transient)	$V_{(BR)DSSt}$	V_{GS} = 0 V, $I_{D(aval)}$ = 8.4 A, T_{case} = 25°C, $t_{transient}$ = 100 ns		34			V
Drain−to−Source Breakdown Voltage Temperature Coefficient	$V_{(BR)DSS}$/T_J				14.4		mV/°C
Zero Gate Voltage Drain Current	I_{DSS}	V_{GS} = 0 V, V_{DS} = 24 V	T_J = 25°C			1.0	μA
			T_J = 125°C			10	
Gate−to−Source Leakage Current	I_{GSS}	V_{DS} = 0 V, V_{GS} = ±20 V				±100	nA
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	$V_{GS(TH)}$	V_{GS} = V_{DS}, I_D = 250 μA		1.3		2.1	V
Negative Threshold Temperature Coefficient	$V_{GS(TH)}$/T_J				4.8		mV/°C
Drain−to−Source On Resistance	$R_{DS(on)}$	V_{GS} = 10 V	I_D = 30 A		4.6	5.8	mΩ
		V_{GS} = 4.5 V	I_D = 18 A		6.8	8.5	
Forward Transconductance	g_{FS}	V_{DS} = 1.5 V, I_D = 15 A			50		S
Gate Resistance	R_G	T_A = 25°C		0.3	1.0	2.0	Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C_{ISS}	V_{GS} = 0 V, f = 1 MHz, V_{DS} = 15 V			1252		pF
Output Capacitance	C_{OSS}				610		
Reverse Transfer Capacitance	C_{RSS}				126		
Capacitance Ratio	C_{RSS}/C_{ISS}	V_{GS} = 0 V, V_{DS} = 15 V, f = 1 MHz			0.101		
Total Gate Charge	$Q_{G(TOT)}$	V_{GS} = 4.5 V, V_{DS} = 15 V; I_D = 30 A			10.9		nC
Threshold Gate Charge	$Q_{G(TH)}$				1.9		
Gate−to−Source Charge	Q_{GS}				3.4		
Gate−to−Drain Charge	Q_{GD}				5.4		
Gate Plateau Voltage	V_{GP}				3.1		V
Total Gate Charge	$Q_{G(TOT)}$	V_{GS} = 10 V, V_{DS} = 15 V; I_D = 30 A			22.2		nC
SWITCHING CHARACTERISTICS (Note 8)							
Turn−On Delay Time	$t_{d(ON)}$	V_{GS} = 4.5 V, V_{DS} = 15 V, I_D = 15 A, R_G = 3.0 Ω			10		ns
Rise Time	t_r				32		
Turn−Off Delay Time	$t_{d(OFF)}$				16		
Fall Time	t_f				6.0		

7. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
8. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Typ	Max	Unit
SWITCHING CHARACTERISTICS (Note 8)							
Turn−On Delay Time	$t_{d(ON)}$	V_{GS} = 10 V, V_{DS} = 15 V, I_D = 15 A, R_G = 3.0 Ω			7.0		ns
Rise Time	t_r				28		
Turn−Off Delay Time	$t_{d(OFF)}$				20		
Fall Time	t_f				4.0		
DRAIN−SOURCE DIODE CHARACTERISTICS							
Forward Diode Voltage	V_{SD}	V_{GS} = 0 V, I_S = 10 A	T_J = 25°C		0.79	1.1	V
			T_J = 125°C		0.65		
Reverse Recovery Time	t_{RR}	V_{GS} = 0 V, dIS/dt = 100 A/μs, I_S = 30 A			31		ns
Charge Time	t_a				15		
Discharge Time	t_b				16		
Reverse Recovery Charge	Q_{RR}				15		nC

7. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
8. Switching characteristics are independent of operating junction temperatures.

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS

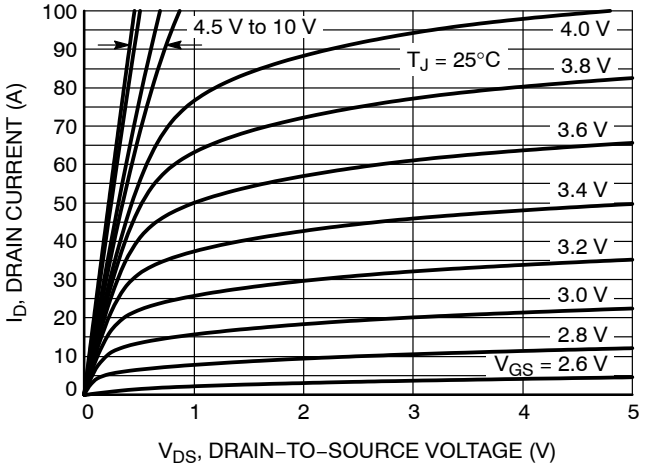


Figure 1. On−Region Characteristics

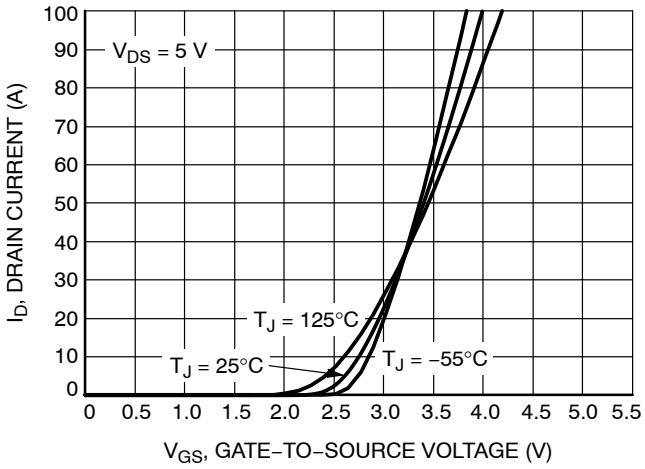


Figure 2. Transfer Characteristics

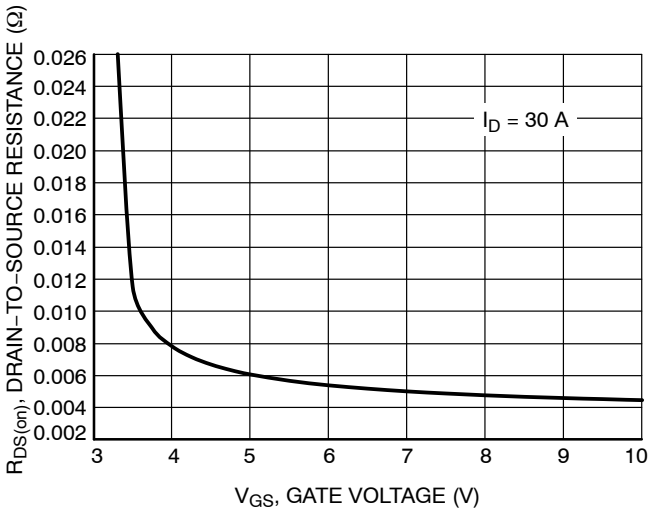


Figure 3. On−Resistance vs. Gate−to−Source Voltage

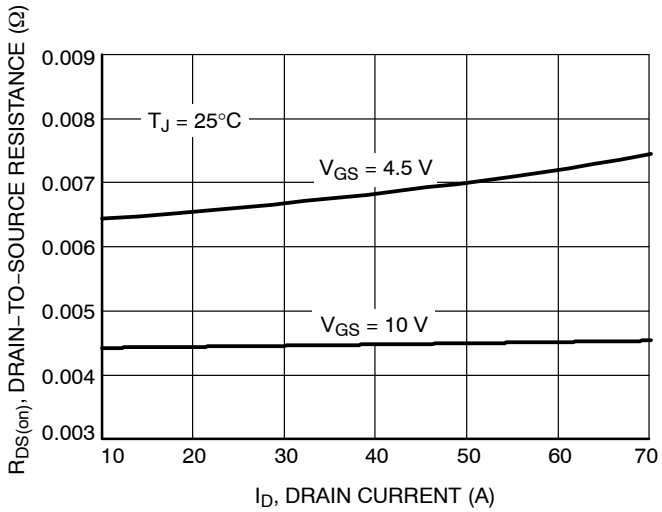


Figure 4. On−Resistance vs. Drain Current and Gate Voltage

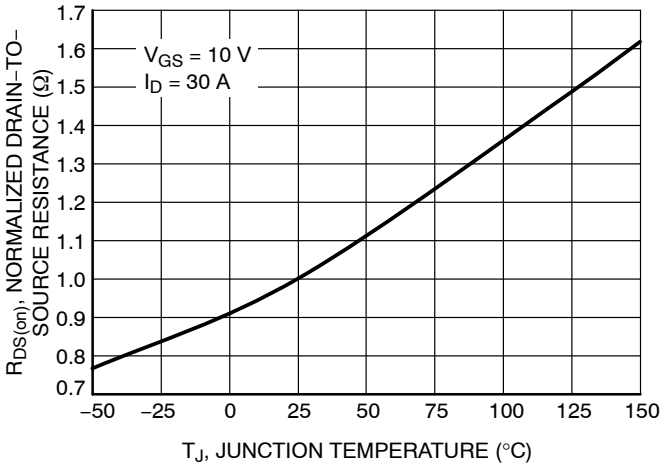


Figure 5. On−Resistance Variation with Temperature

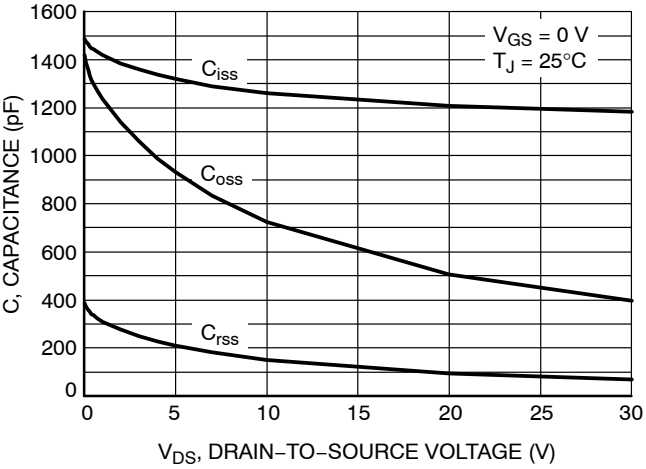


Figure 6. Capacitance Variation

TYPICAL CHARACTERISTICS

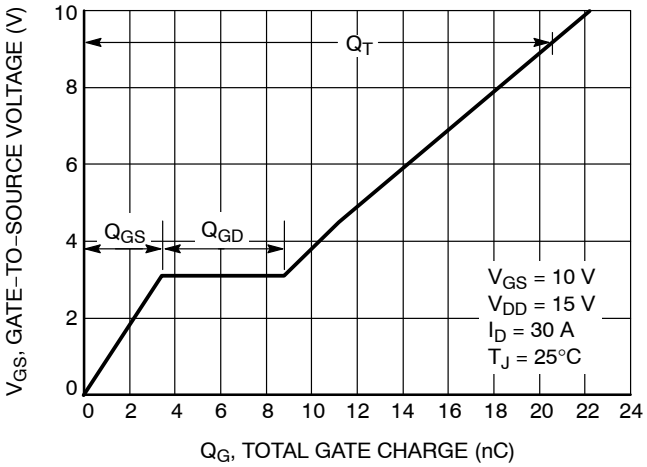


Figure 7. Gate−to−Source and Drain−to−Source Voltage vs. Total Charge

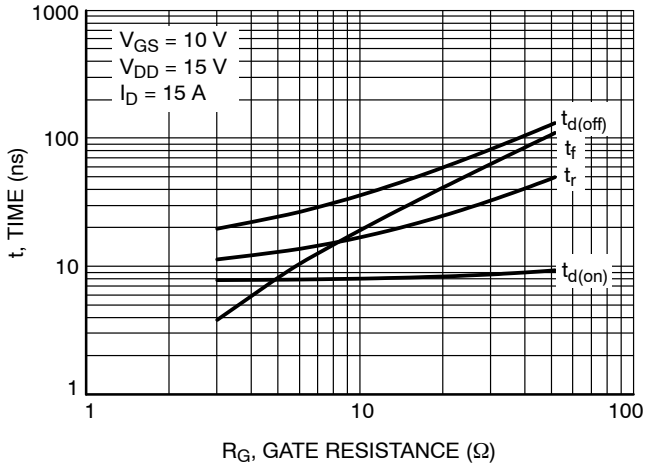


Figure 8. Resistive Switching Time Variation vs. Gate Resistance

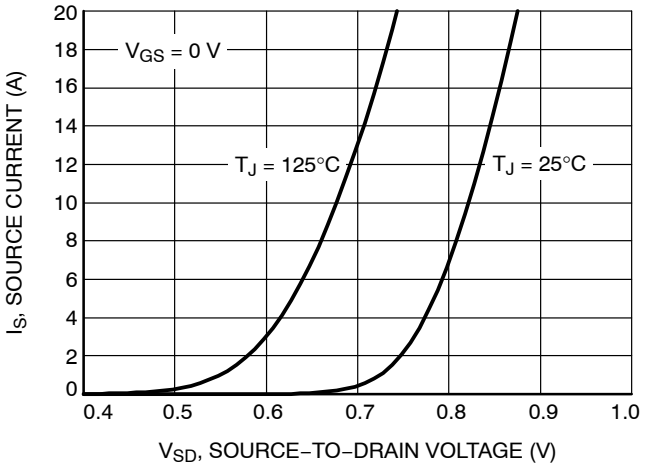


Figure 9. Diode Forward Voltage vs. Current

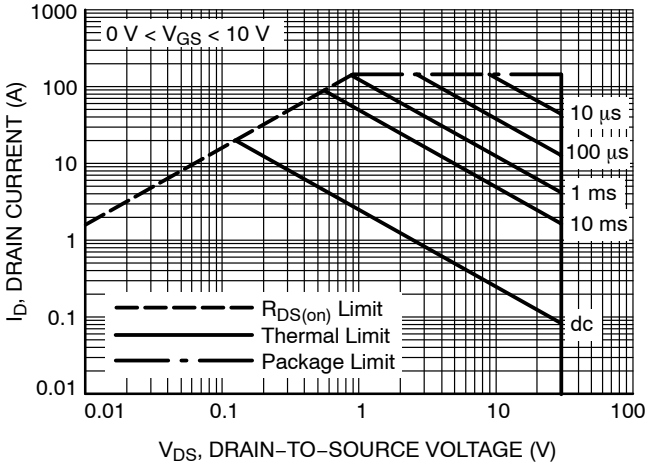


Figure 10. Maximum Rated Forward Biased Safe Operating Area

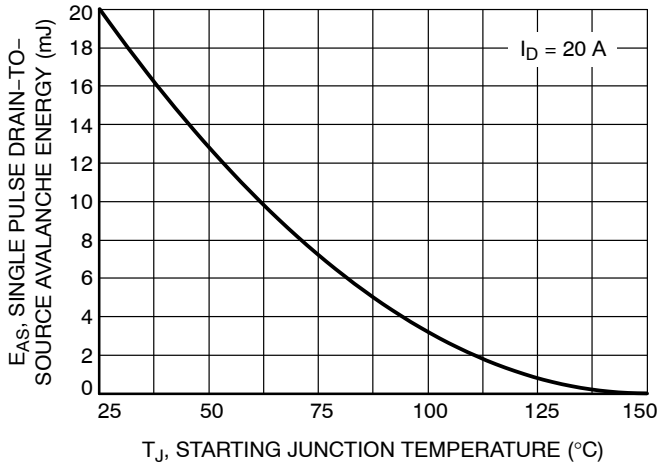


Figure 11. Maximum Avalanche Energy vs. Starting Junction Temperature

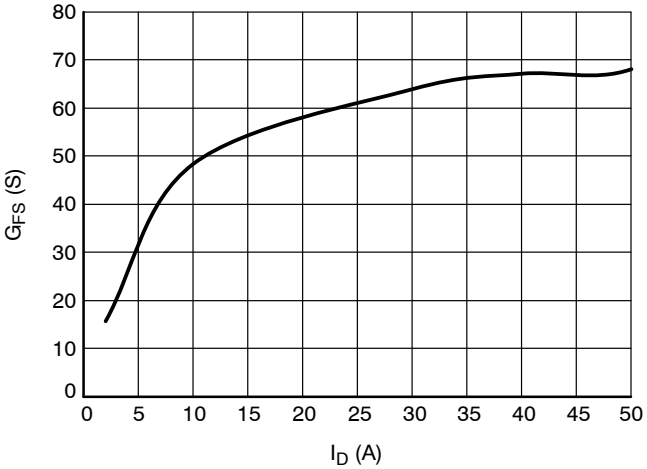


Figure 12. G_{FS} vs. I_D

TYPICAL CHARACTERISTICS

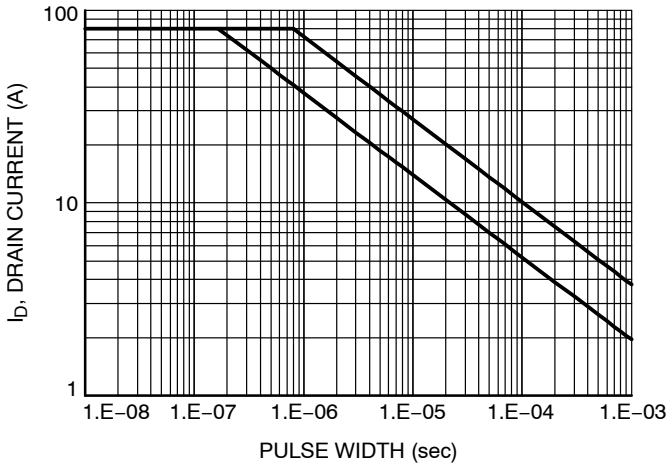


Figure 13. Avalanche Characteristics

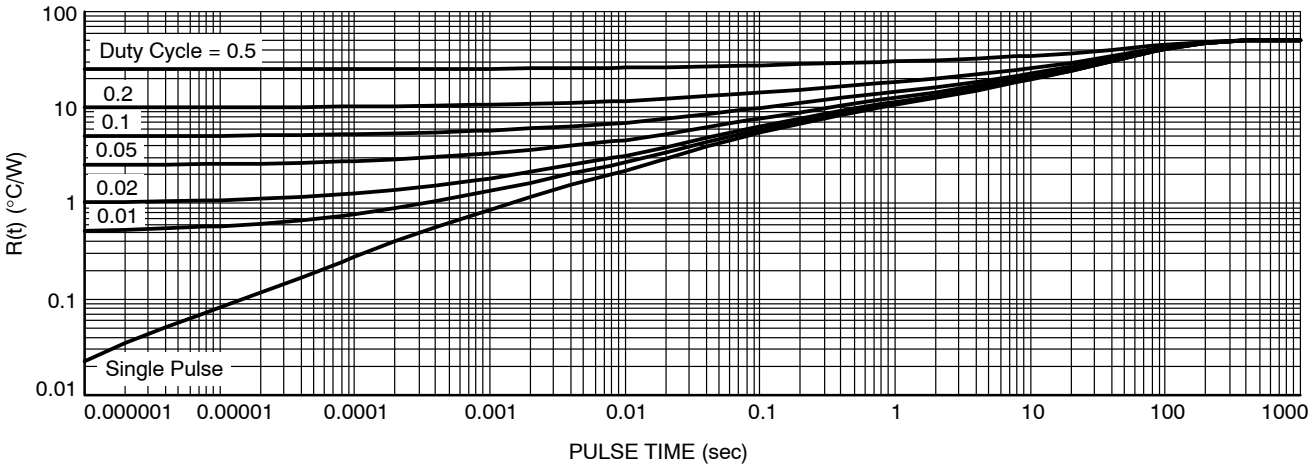


Figure 14. Thermal Response

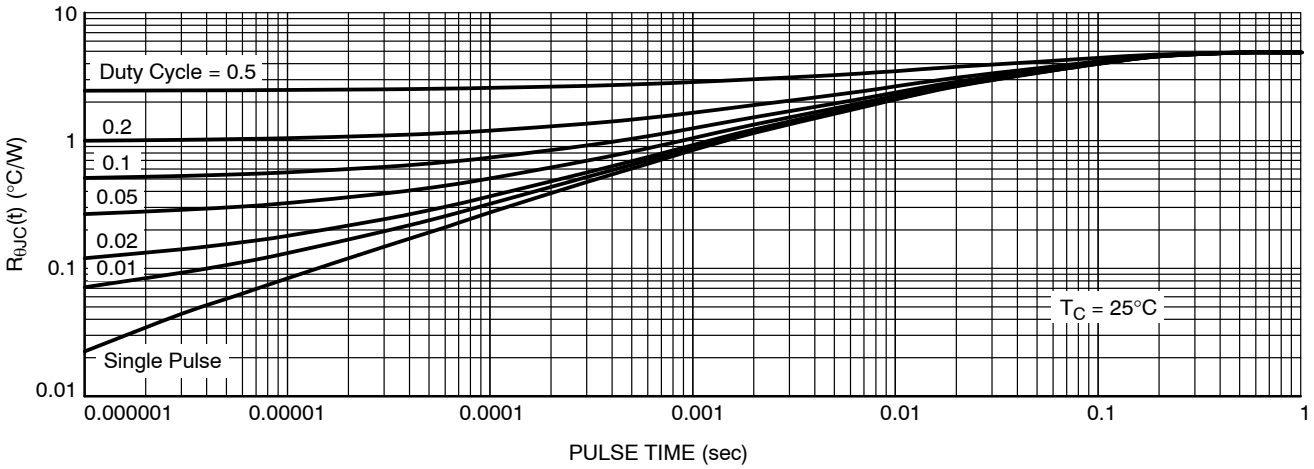
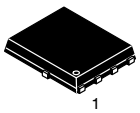


Figure 15. Thermal Response

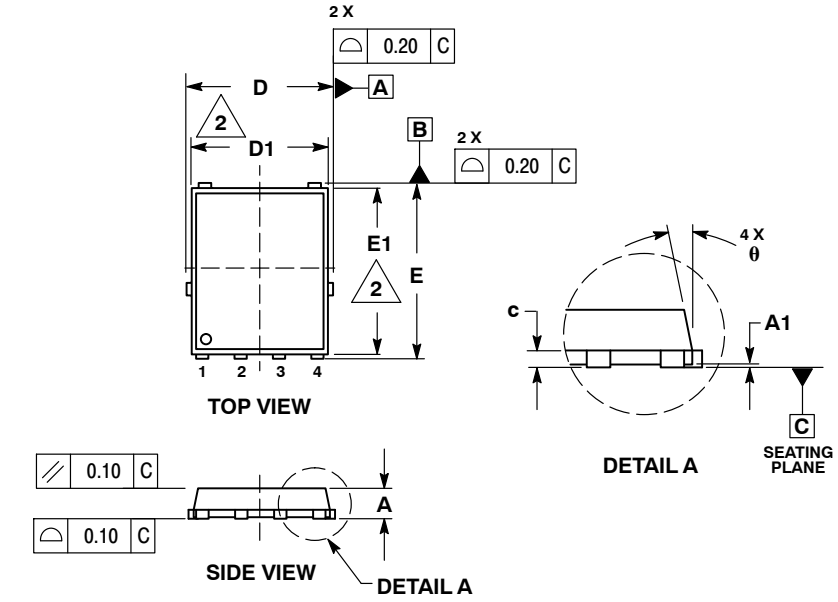
MECHANICAL CASE OUTLINE
PACKAGE DIMENSIONS



SCALE 2:1

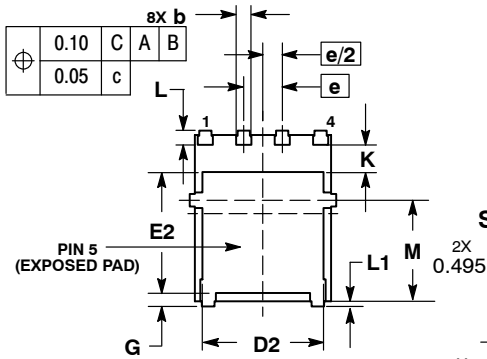
DFN5 5x6, 1.27P
(SO−8FL)
CASE 488AA
ISSUE N

DATE 25 JUN 2018

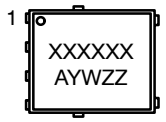


NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS		
DIM	MIN	NOM	MAX
A	0.90	1.00	1.10
A1	0.00	–––	0.05
b	0.33	0.41	0.51
c	0.23	0.28	0.33
D	5.00	5.15	5.30
D1	4.70	4.90	5.10
D2	3.80	4.00	4.20
E	6.00	6.15	6.30
E1	5.70	5.90	6.10
E2	3.45	3.65	3.85
e	1.27 BSC		
G	0.51	0.575	0.71
K	1.20	1.35	1.50
L	0.51	0.575	0.71
L1	0.125 REF		
M	3.00	3.40	3.80
θ	0 °	–––	12 °



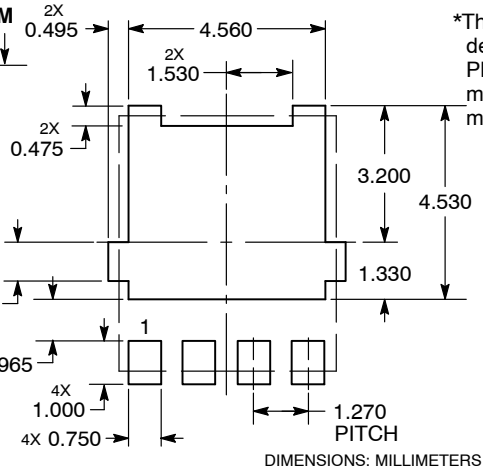
GENERIC MARKING DIAGRAM*



XXXXXX = Specific Device Code
A = Assembly Location
Y = Year
W = Work Week
ZZ = Lot Traceability

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, “G” or microdot “ ▪”, may or may not be present. Some products may not follow the Generic Marking.

RECOMMENDED SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

STYLE 1:
PIN 1. SOURCE
2. SOURCE
3. SOURCE
4. GATE
5. DRAIN

STYLE 2:
PIN 1. ANODE
2. ANODE
3. ANODE
4. NO CONNECT
5. CATHODE

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	**DFN5 5x6, 1.27P (SO−8FL)**	**PAGE 1 OF 1**

ADDITIONAL INFORMATION

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